

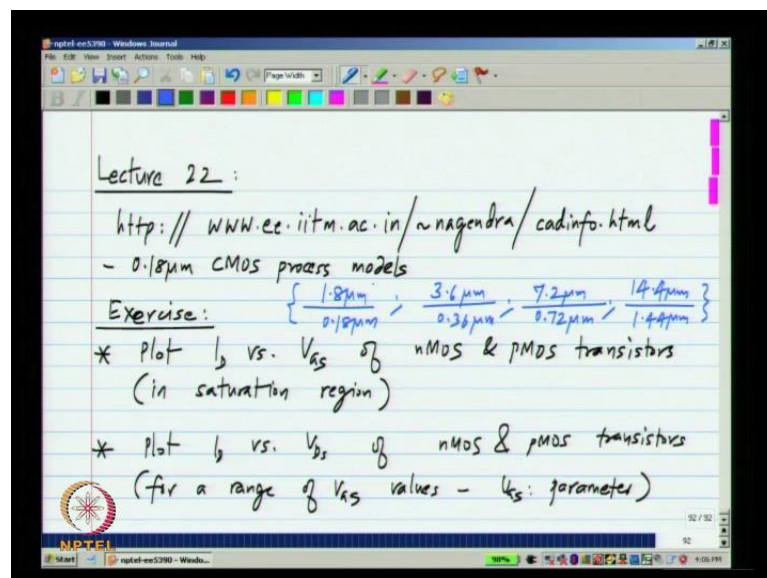
**Analog Integrated Circuit Design**  
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**Lecture - 22**  
**MOS Transistors – Parasitic Mismatch**

Hello and welcome to the twenty second lecture of analog integrated circuits design. In the previous lecture, we discussed the large signal model of the mos transistor as it appears on integrated circuits. In some details, we saw that it eta square law when the  $V_{DS}$  is greater than a certain amount. We also saw that the bulk voltages has a significant influence on the current in the mos transistor, this is because the bulk and the gate are similar in a mos transistor.

They play similar rules in an nMOS transistor, increasing the gate voltages for the bulk voltage increases the amount of charge in the channel and least shown increase in the current modeling the effect of the bulk is quite important. In a MOS transistor especially in integrated circuits, we also discussed the behavior of the MOS transistor when the  $V_{GS}$  is below the threshold voltage and we saw that it turns out to be an exponential. Now as I also mentioned in the last class, the real model of MOS transistor is very complicated. So, you have to use a simulator to gain better understanding of the MOS transistor.

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The image shows a screenshot of a presentation slide titled "Lecture 22". The slide contains the following text:

Lecture 22 :

<http://www.ec.iitm.ac.in/~nagendra/cadinfo.html>

- 0.18 $\mu$ m CMOS process models

Exercise: { 1.8 $\mu$ m / 0.18 $\mu$ m, 3.6 $\mu$ m / 0.36 $\mu$ m, 7.2 $\mu$ m / 0.72 $\mu$ m, 14.4 $\mu$ m / 1.44 $\mu$ m }

\* Plot  $I_D$  vs.  $V_{GS}$  of nMOS & pMOS transistors (in saturation region)

\* Plot  $I_D$  vs.  $V_{DS}$  of nMOS & pMOS transistors (for a range of  $V_{GS}$  values -  $V_{GS}$ : parameter)

The slide also features a logo for NPTEL (National Programme on Technology Enhanced Learning) in the bottom left corner and a page number "92 / 92" in the bottom right corner.

So, what I suggest is that, I take it as an exercise to get hold of some MOS transistor models. In fact, some models are available from these websites. The number of models available, you can choose the 0.18micron pMOS process models and you take these models, get familiar with the circuits simulator. There is the number of circuits simulators available both free and commercial simulators. You can download some of the free ones from the web and the kind of exercise that I am going to mention, can be very done on a free simulator. So, please do the following, what  $I_d$  versus  $V_{GS}$  of nMOS and pMOS transistor.

When I say  $V_{GS}$  for pMOS transistor it means the  $V_{GS}$  of course in saturation region and similarly plot  $I_d$  versus  $V_{DS}$  of a nMOS and pMOS transistors for a range of  $V_{GS}$  values that is with a  $V_{GS}$  as a parameter. Now, you will have to do this kind of exercises any way when you come across the process for the first time. Now, this also helps you understand the limitation of the models that we have. The models you have on this website are quite complicated and they model the MOS transistor very elaborately.

So, when you do these two things, let us say you chose the 0.18 micron CMOS process as I mentioned earlier. When you specify a length of a process, it means usually the minimum gate length that is possible for a MOS transistor. You try this for different values of  $W$  by  $L$ . So, let us say, I will say 1.8 micron by 0.18 microns. You can double both of them, similarly double it further.

Let us say you take these four values, you could also take other things in between the point of this value that all of them have a  $W$  value ratio of 10, but as I mentioned earlier, there are lots of effects which make the transistor characteristic deviate from square law. Now, one thing that we did not discuss is the short channel effect. When the channel length becomes very small then, it is definitely not a square law device it turns out when the channel length is very short, it is not a square law device. Now, again we have not discussed the device physics.

It is not a square law device, now again we have not discussed the device physics, but the square law comes from different dependence on  $V_{GS}$  minus  $V_T$ . First of all the amount of charge depends on  $V_{GS}$  minus  $V_T$  and the electric field inside the device depends on  $V_{GS}$  minus  $V_T$  and in a certain region the velocity of the carriers is directly proportional to the electric field.

So, the total current is related to the number of carriers which is related to the total amount of charge times. The velocity of the charges since each of this is depended on  $V_{GS} - V_T$ ; we get  $V_{GS} - V_T$  square. Now, it turns out that, as you increase the electric field beyond some limits the velocity of the carriers becomes saturated, this is known as velocity saturation.

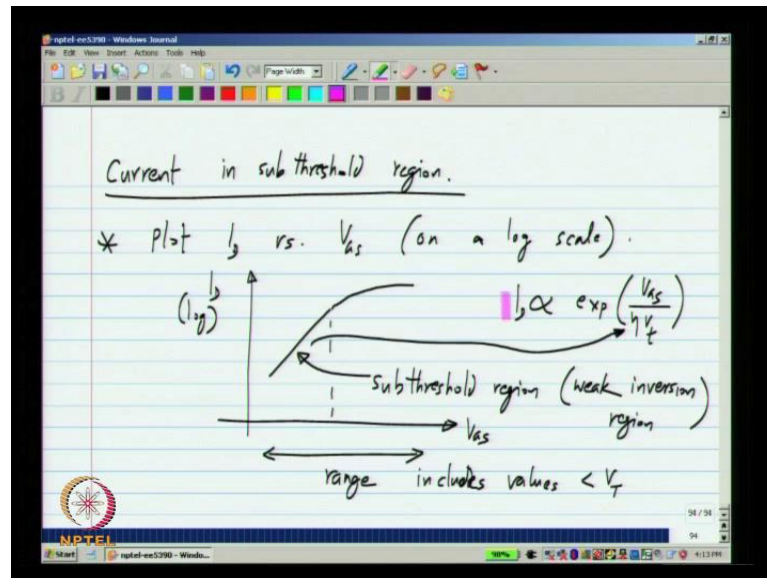
So, at this point the velocities of the carrier's no longer increase with apply of electric field. So, this means now the total current equals the product of speed which is more or less constant with times amount of charge which is proportional to  $V_{GS} - V_T$ . So, the current instead of being what you end up getting, it turns out that this is the speed of the carrier. So, the velocity saturated current is given by something proportional to be  $V_{GS} - V_T$  and the saturation velocity of the carriers because of this reason the transistor current does not obey an exact square law dependence with  $V_{GS}$ .

Also another thing to keep in mind is that, the regions are not appropriately divided here. We have the velocities saturation and here we do not like all physical phenomena. This happens continuously, so the bottom while is that, if you do the characterization for these sets of channels length and channel width let us say 1.8 micron by 18 micron or all the way to 14.4 microns by 1.44 microns, all of them have a  $W$  by  $L$  ratio of 10.

But, you will see that the behavior will be quite different. In fact, in particular you should try to identify these things. The reason in which the square law is not obeyed and this can be found from the plot of  $I_d$  versus  $V_{GS}$  in the saturation region and also by plotting either  $I_d$  versus  $V_{GS}$  or square root of  $I_d$  versus  $V_{GS}$ . You will also be able to identify this threshold voltage, which is used in our simple model and the  $I_d$  versus  $V_{GS}$  will give you the value of  $\lambda$ .

Another thing how the transistor current depends on the  $V_{DS}$  in the saturation region, how it depends on that in the dry out region and so on? Finally, if you absorb properly, you should see that as you increase the channel length to very large values, it will obey square law and as you reduce the value of channel length, it will not obey the square law, but you should still be able to design circuit with this transistor, whether the current obey square law or not. So, this is one of the exercises. The other exercise is to find out the current in sub threshold region for this.

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What you do is plot  $I_D$  versus  $V_{GS}$  on a log scale as you know the log scale is used when the quantity is over a wide range and as I said, when  $V_{GS}$  goes below the threshold voltage the current will be so small that it can be meaningfully represented only on a log scale. You can plot  $I_D$  versus  $V_{GS}$  and you cover a range of  $V_{GS}$  which includes values less than  $V_T$ . Now, already said that  $I_D$  will be proportional to exponential  $V_{GS}$  divided by the thermal voltage times some factor  $\eta$ , now if you recall a perfect bipolar transistor will have  $\eta$  equal to one.

A MOS transistor will not have a  $\eta$  equal to one. In fact, all of these things you can estimate from this plot. When it is following the exponential the curve  $I_D$  versus  $V_{GS}$ , where  $I_D$  is a log scale, will be a straight line and this will be the sub-threshold region or the weak inversion region and when you go above the threshold region, it is square law which means it is less compared to exponential and it does something like that.

So, the point of this exercise is first of all to identify the sub-threshold region and secondly from this region you can get the slope  $\eta$ . You can calculate the slope of this straight line and from that find the factor  $\eta$ . We will discuss this a little more later, but you can see that, if  $\eta$  is close to 1, then it is better because the exponential will be really steep, so that is the point of this exercise and do this for both nMOS and pMOS and similar rise yourself with the MOS transistor.

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\* Find the effect of  $V_{sb}$

\* Plot  $I_D$  vs.  $V_{sb}$   
 ( $V_{gs}, V_{ds}$ : strong inversion & saturation)

\* Plot  $I_D$  vs.  $V_{ds}$  for different values of  $V_{sb}$   
 ( $V_{sb}$ : parameter)

$V_{sb} > 0$

Now, finally the third exercise would be to find the effect of  $V_{SB}$ , you take a MOS transistor and set with the fixed  $V_{GS}$  and  $V_{DS}$  and varying  $V_{SB}$ . Let us assume  $V_{SB}$  more than zero, so that you do not forward bias the source of bulk junctions. Now, you can plot  $I_D$  versus  $V_{SB}$ , let us assume that you maintain  $V_{DS}$  and  $V_{GS}$ , so that it is in strong inversion and saturation. So, this is one of the exercises and secondly you can also plot  $I_D$  versus  $V_{DS}$  for different values of  $V_{SB}$  with  $V_{SB}$  as a parameter. Remember, earlier you plotted  $I_D$  versus  $V_{DS}$  with  $V_{GS}$  as a parameter for different values of  $V_{GS}$ .

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dc Small signal model of the MOS transistor:

$I_D = f(V_{gs}, V_{ds}, V_{sb})$

$\Delta I_D = \frac{\partial I_D}{\partial V_{gs}} \Delta V_{gs} + \frac{\partial I_D}{\partial V_{ds}} \Delta V_{ds} + \frac{\partial I_D}{\partial V_{sb}} \Delta V_{sb}$

$g_m$ ,  $g_{mb}$ ,  $g_{ds}$

You would get different saturation currents. Now, if you do the exercise correctly you will see the same effect with  $V_{SB}$  as well. This is again to convince yourself that the back gate and the front gate qualitatively. Similarly, quantitative functions there will be different from each other. So, the previous lecture plus all this exercise should give you a very good idea to handle on the large signal characteristics of the MOS transistor.

So, now move on to small signal model with the MOS transistor because the  $I_D$  is a function of  $V_{GS}$ ,  $V_{DS}$  and  $V_{SB}$ . In the small signal case it usually is written as a function of  $V_{BS}$ . We know that the change in  $I_D$  will be a function of change in  $V_{GS}$ , change in  $V_{DS}$  and also change in  $V_{BS}$ . What kind of function it will be, we know that when the changes are small it will be a linear function.

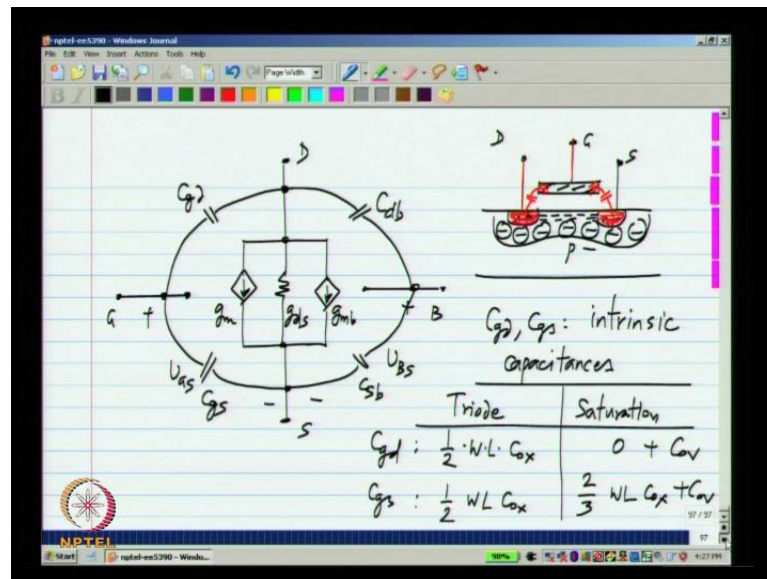
So,  $\Delta I_D$  will be partial derivative of  $I_D$  with respect to  $V_{GS}$  at the operating point times  $\Delta V_{GS}$  plus partial derivative with respect to  $V_{DS}$ . Again at the operating point which is very important times  $\Delta V_{DS}$  plus partial derivative with respect to  $V_{BS}$  times  $\Delta V_{BS}$ . Now, it is common to denote changes by lower case letters which is what I am going to do from here onwards.

This is  $V_{GS}$ ,  $V_{DS}$  and  $V_{BS}$  and this could be represented instead of  $\Delta I_D$  as lower case  $i_d$ , this behavior is what is captured by a small signal model of the MOS transistor. So, first of all the dependence of  $I_D$  on  $V_{GS}$ , we need to have a control source. This is a linear control source, like everything in the small signal model is linear and the value of the control sources  $\frac{dI_D}{dV_{GS}}$ . So, we have four terminal drain gates bulk and source. So, between the drain and source will have a control current source and this denote this particular current and this constant aware are called  $g_m$ ?

Now, this current is  $g_m$  times  $V_{GS}$ , where  $V_{GS}$  is the small signal, gate source voltage similarly, this current can be represent by another control source and this constant here  $\frac{dI_D}{dV_{BS}}$  is like  $g_m$ , but from the bulk. So, it is usually denoted by  $g_{mv}$  and in the small signal case we use  $V_{BS}$  instead of  $V_{SB}$ , that is the convention and this control sources  $g_{mb}$  times  $V_{BS}$  and finally, this current here relates the current from drain to source as a function of voltage between drain and source. We could use a control current source but it is easier to just model it as conduction because the controls in terminals on where the current is flowing are the same and this quantity is none as  $G_{DS}$ .

So, this is the conductance which is GDS. Now, this is the DC small signal model of the MOS transistor. The left more source, it denotes the current from drain to source based on the increment in VGS, the conductance GDS denotes the dependents on a drain to source current on the drain. The small signal sense and finally, gmb times VBS denotes the dependency on brink current on the bulk source voltage and because this does not include any capacitor or charge storage effect, it is the DC small signal model of the MOS transistor.

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So, this is what we will use for Dc small signal and analyses here onwards. I will simply gm here, it is understood that it multiplies VGS and will write gmb and it is assumed that it multiplies VBS and I will write GDS here. This is just to simplify the diagram and reduce plotter. Now, this is the Dc small signal models in addition to this let us take again nMOS transistor. Now, first of all there will be capacitance between the gate and channel because after all that is what the MOS transistor is. It is a capacitance that is form between the gate and the inversion layer when the transistor is on, so this contributes to some capacitance in this circuit.

Now, this is really a distributed capacitance which goes between the gate which stretches all the way from here to there and the inversion layer which also stretches all the ways form here to there. Now, we have to represent a capacitor between discreet terminals drain gate and source. So, what we will do is we will apportion the capacitance into two

parts one between the drain and gate and one between gate and source this is called  $C_{gd}$  and this is called  $C_{gs}$  due to the depletion region there will be the capacitance between drain and bulk which is  $C_{db}$  and between source and bulk which is  $C_{sb}$ . Primarily due to the depletion region below this diffusion regions. Now, these are the  $C_{gd}$  and  $C_{gs}$  intersect to the operational the mosfet as we know mosfet is nothing, but a capacitor and it controls the charge and inversion layer and in turns control the current. So, this capacitance will always be present whenever you have a mosfet without this capacitor. There is no mosfet because the  $C_{ga}$  and  $C_{gs}$  what we describe so far come from the intrinsic capacitance between the gate and the inversion region.

So, this is known as intrinsic capacitances and the value of these things depend on the operating point. It turns out that in triode region  $C_{gd}$  and  $C_{gs}$  are both equal to half of  $W$  times  $L$  times  $C_{ox}$ . This  $W$  times  $L$  is nothing, but area of the gate and  $C_{ox}$  is the capacitance per unit area of the oxide under the gate  $W$  times  $L$  times  $C_{ox}$  is the total capacitance of the gate, I mean triode reason this are equally opposite and in between the drain and the source both  $C_{gd}$  and  $C_{gs}$  equal half  $WL C_{ox}$ . Now, this you can easily imagine the case where the drain and source voltages are identical then the channel will be perfectly symmetrical and then clearly the configuration between the gate and drain will be the same as that between gate and source.

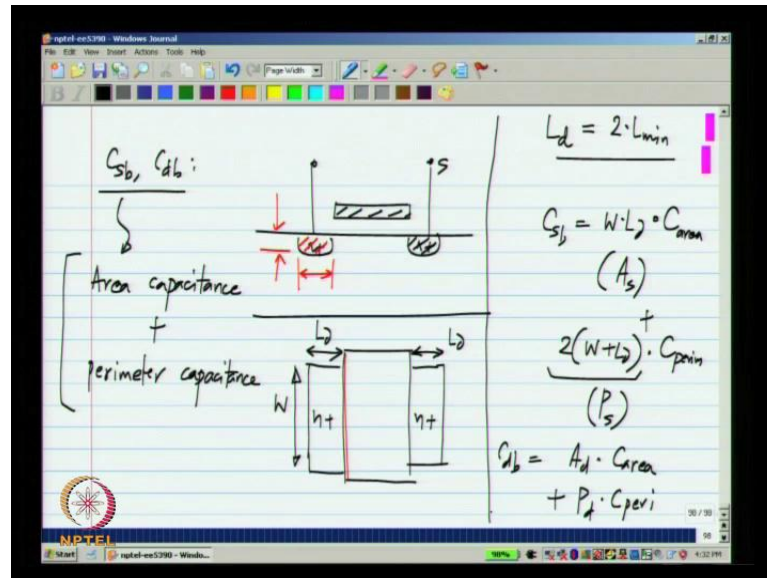
So, the proportion of charges allocated to drain and source are identical as you go far away from deep region the charge distribution becomes less and less symmetrical and we will have a different charges distribution. In the extreme case saturation region  $C_{gd}$  will be zero and  $C_{gs}$  will be two- third  $WL C_{ox}$ . This comes from device physics by calculating the amount of charge in the inversion layer the total charge is two third  $SWL C_{ox}$  and all of it is the appropriation to the source. Now, nothing is appropriate to the drain because at the drain the channel is not inverted and there is pinch of layer. So, nothing is really connected to the drain. So, these are the values of  $C_{gd}$  and  $C_{gs}$  by the way this model is valid in all regions including gm<sub>VS</sub> and gm<sub>GDS</sub> only.

Question is what are the values of those things now? Will it be using this model mostly in a saturation region because that is why we operate our amplifier, but the model itself is valid everywhere. Now, this is about the intrinsic capacitor in addition to this you see that you have some conducting material here. In addition to this you could also have these wires and you have the conducting gates and between these two there will be a



capacitance. This is not inherent to the operation the mosfet, but it is there simply because the two pieces of conducting material are close to each other. So, the actual  $C_{gd}$  and  $C_{gs}$  will consist of this and some overlap capacitance.

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Now, again drawing a picture of mosfet you want to calculate the overlap capacitance between these two. You imagine the top view, where the gate is like that and the drain and source region are like that, now this capacitance nothing, but the fringing capacitance between this conductor which is the gate and this is which is the drain you can easily see that, the capacitance will be proportional to the width of the overlap which is nothing, but the width of the mosfet.

Something proportional to the width and it is the same thing is for  $C_{sb}$  as well. So, I will denote this as  $C_{oe}$  prime which is the capacitance per unit with times the width of the mosfet and exactly the same thing for  $C_{gs}$  as well this is plus  $u$  times  $W$ . So, those are extrinsic capacitance, but they will be there any way till you have a mosfet. So, you also have to model them, now regarding  $C_{sb}$  and  $C_{db}$   $C_{sb}$  is the basically the junction capacitance of the source junction. This one and  $C_{db}$  is the junction capacitance of that junction. Now, exactly how much the capacitance is depends on the area of this phase. The bottom phase of this and also the side phase of this now again. If you look at the top view of the MOS transistor, this diffusion region  $n+$  plus will have some length late call that  $L_d$  and this usually as the same length  $L_d$  and typically as a guide line if you do not

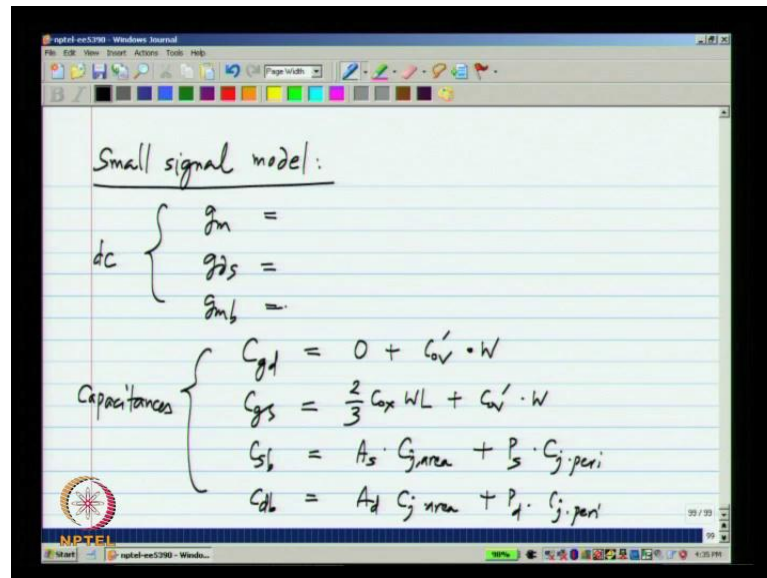
have any other information, you can assume that  $L_d$  is two times the minimum length of the gate and in a given technology and this dimension is nothing, but  $W$  as usual we do not have control over this depth, that is why we do not want any parameter describing the depth. If you know the depth, the depth times  $W$  is the side wall area, but we do not want any of that the depth is fixed.

So, the capacitance is described as being made of two pieces one which is the overlap area at the bottom which depends on  $W$  times  $L_d$ . So, each of these things consists of what are usually called the area capacitance which refers to the overlap area at the bottom plus some perimeter capacitance as I describe while defining the sheet resistance and so on. In an integrated circuit, we have control over only the two dimensions.

So, all the other dimensions are subtracted into parameters and we will describe everything into dimension that we can control which is  $L_d$  and  $W$  and so on. The area capacitance part is given by  $W$  times  $L_d$  which is usually called as the area of the source times. Some capacitance per unit area plus the perimeter of this which is two times  $W$  plus  $L_d$  times  $c$  perimeter and this parameter is usually denoted  $p_s$  while you describe the mosfet in a simulator. Now, we are of course, looking at regular structure which have a rectangle area, but you could also have other odd shape.

So, then you specify the area and the perimeter directly of the source and drain junction similarly, for the  $C_{db}$  we will have  $a_d$  that is the drain junction area times the capacitance per unit area plus the drain junction perimeter times the capacitance per unit perimeter, now this all are detail, but you need to know these things when you want to describe in a simulator. When you model a mosfet in a simulator, you also have to put in appropriate perimeter and area values for the mosfet, so that you model all these capacitances. We later see that all these capacitances will have significant influence on the operation for the circuit. So, it is very important to understand these models and then use them properly.

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So, just to summarize the small signal model of the mos transistor consist of dc parameters which are gm, gds and gmb and capacitances which are Cgd, Cgs, Csb and Cdb between every pair of terminal you have a capacitance except being source and drain directly because they are kind of isolated from each other and that capacitance generally small in most processes and in saturation region the intrinsic value of Cgd is zero, but you will have the overlap capacitance per unit length times the width of the mosfet Cgs will be two third Cs WL plus this times the width mosfet Csb and Cdv are junction capacitance and largely independent of the region of the operation of the MOS transistor.

We will of course, assume that this junction are revised by us, otherwise this capacitance equals to be very different and it is area of the source junction times the source junction capacitance may be explicitly mention, that I will say Cj area plus the perimeter of the source junction times Cj perimeter and this will be area of the drain junction times Cj area because the junction are of the same type they are same Cj area applies to both Cj and Cdb plus pd times Cj perimeter and gm, jds and gmb can be calculated in the saturation region. We can also calculate it in the try out region, but because saturation region is of greater interest what is will use.

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The image shows a handwritten derivation on a digital notepad. The first equation is the drain current  $I_D$  for an nMOS transistor in saturation, given by the square-law model: 
$$I_D = \frac{\mu_n C_{ox}}{2} \cdot \frac{W}{L} (V_{GS} - V_T)^2 (1 + \lambda V_{DS})$$
 The second equation shows the transconductance  $g_m$  as the derivative of  $I_D$  with respect to  $V_{GS}$ : 
$$g_m = \frac{\partial I_D}{\partial V_{GS}} = \mu_n C_{ox} \cdot \frac{W}{L} (V_{GS} - V_T) (1 + \lambda V_{DS})$$
 The third equation shows an approximation where the channel length modulation term  $(1 + \lambda V_{DS})$  is neglected, indicated by a curved arrow: 
$$\approx \mu_n C_{ox} \cdot \frac{W}{L} (V_{GS} - V_T)$$
 The fourth equation shows the relationship between  $g_m$  and  $I_D$ : 
$$= \frac{2 \cdot I_D}{V_{GS} - V_T}$$
 The final equation shows the square-root form of the transconductance: 
$$= \sqrt{2 \cdot \mu_n C_{ox} \cdot \frac{W}{L} \cdot I_D}$$

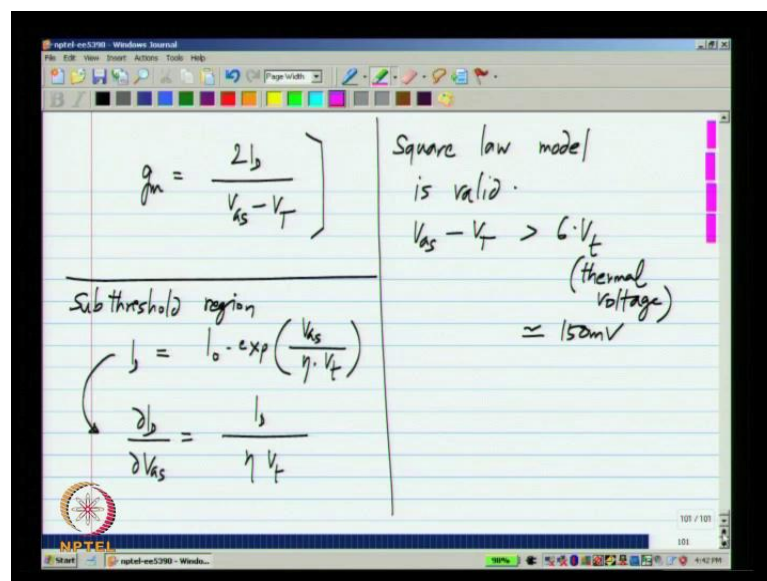
So, again will start from the square law which basically assume a strongly inverted mosfet operating with  $V_{DS}$  greater than  $V_{GS}$  minus  $V_T$  and I will do my calculation with an nMOS transistor, but they can be easily be translated to a pMOS transistor, This is the expression for the current and the trans conductance  $g_m$  is given by  $\partial I_D / \partial V_{GS}$  which is equal to  $\frac{1}{2} \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_T)^2 (1 + \lambda V_{DS})$ . Now, first of all this  $\lambda V_{DS}$  is expected to be relatively small quantity compare to one now, this is largely to except on channel length is very short.

Now, for simplicity hand calculation any times this is simply approximated into  $\mu_n C_{ox} \frac{W}{L} (V_{GS} - V_T)$ . Now, if you look at it can also be written as two times the drain current divided by  $V_{GS} - V_T$  and also you can neglect this, one plus  $\lambda V_{DS}$  and write it in terms of only  $I_D$   $2 \mu_n C_{ox} \frac{W}{L} I_D$ . So, this are all just rearrangement of the same expression and here and there we will omit the one plus  $\lambda V_{DS}$ , that is we have to replace one plus  $\lambda V_{DS}$  by just one for simplicity and this is kind of thing that you have do for hand calculations. There is no point including kinds of small detail from the model itself is accurate. When you want really accurate answer you go to stimulator, but it is very important to do hands calculations because you know which circuits has to be modified when it does give you the result you want. No three expressions appear to show different dependence of a  $g_m$  over the electrical quantities  $V_{GS} - V_T$  and  $I_D$ .

Now, the first one says this is proportional to  $V_{GS} - V_T$  at the second one says it is inversely proportional, but there is no contradiction here. This is the function only  $V_{GS} - V_T$ , but this is the function of  $I_d$  and  $V_{GS} - V_T$ . If we change  $V_{GS} - V_T$  for a given transistor  $I_d$  will also change, hence you have to take that into account. So, do not get confused by this and finally the last one says, it is proportional to square root of  $I_d$ , but this is expressed only in terms of  $I_d$ .

So, each of these we will use in the right context because many times you change one parameter and you would like to find the influence of only that parameter. So, let us say you change only  $V_{GS}$ , then the first expression is most convenient and let us say you make some manipulation by which you change only the drain current then the last one is most convenient and the second is also quite convenient sometimes when you want to get inside into the operation of the circuits

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Now, it is the second one that I want to discuss in a little more detail. It says that  $g_m$  is two  $I_d$  by  $V_{GS} - V_T$ , now this seems to suggest that if I go on reducing  $V_{GS} - V_T$ , while maintaining a constant current and how can I do this? I can go on increasing width of the transistor and reducing  $V_{GS} - V_T$ . We know that  $I_d$  is proportional to  $W$  by  $L$  and also proportional to  $V_{GS} - V_T$  square.

So, I can reduce  $V_{GS} - V_T$  and increase  $W$  by  $L$  and keep current the same and this thing says that as  $V_{GS} - V_T$  approaches 0,  $g_m$  approach to infinity. So, you really

think that will be the case. Some what really happens that the square law model is valid only when  $V_{GS} - V_T$  is greater than about  $6 V_T$ , where this is the thermal voltage. Now, when  $V_{GS}$  approaches close to  $V_T$ , then the square law model itself is invalid, it is valid only when  $V_{GS} - V_T$  is more than about  $6 V_T$  or approximately 150 millivolts.

Now, for  $V_{GS} - V_T$  value is below this, you cannot use square law model. So, this expression which is derived from the square law model is also invalid. Now, what happens in the sub threshold region  $I_D$  is given by some  $I_0$  exponential  $V_{GS}$  divided by  $\eta$  times the thermal voltage, where  $\eta$  is some parameter and you have to calculate the  $g_m$  from this expression and if you do that you will see that it will be  $I_D$  divided by  $\eta V_T$ .

Now, this expression are in a similar form, the first one can be thought of  $I_D$  divided by half of  $V_{GS} - V_T$  and the second one is  $I_D$  divided by  $\eta V_T$ . So, what happens is you imagine a case, where that transistor buyer with large  $V_{GS} - V_T$ , then you go on increasing the  $W/L$  and go on reducing the  $V_{GS} - V_T$ , while maintaining the current to be constant. This is possible with some combination off decreasing  $V_{GS} - V_T$  and increasing  $W/L$ .

Now, what happen is as  $W/L$  increases large value which is minus reduce the  $g_m$  value will saturate. We will not go on indefinitely increasing. This happens when transistor enters sub threshold region. So, this is a an example of where you can calculate expression based on same module and then it seems to give you upset result, but it turns out that the model itself is invalid. Now, the other thing this says is that for a given current where you would operate in other regions you would operate to get the maximum  $g_m$ .

Later we will see that getting a large  $g_m$  is a very important thing in electronic circuits,  $g_m$  is something like the gain of the transistor, so getting the large  $g_m$  is quite important and you can easily see from this expression, that if you want a large  $g_m$ , we should operate with  $W/L$  small minus  $V_{GS} - V_T$  possible. And in fact push the transistor into the sub threshold region. You use a very large transistor and by a sheet with their relatively small current, then you get the largest value of  $g_m$  divided by  $I_D$  that is you can get MOS bank for the meaning, you get the value of  $g_m$  with the smallest amount of

current or for a given current you get the largest possible gm and this are all things that we will use later when scaling circuits etc. But, again something to be kept in mind because this is how the small signal parameter behaves.

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Small signal model:

DC

$$g_m = \frac{2I_D}{V_{GS} - V_T} \text{ (strong inv.) ; } \frac{I_D}{\eta V_T} \text{ (weak inv.)}$$

$$g_{mS} = \lambda \cdot I_D$$

$$g_{mB} = g_m \cdot \frac{\partial V_T}{\partial V_{SB}}$$

Capacitances

$$C_{gd} = 0 + C_{ov} \cdot W$$

$$C_{gs} = \frac{2}{3} C_{ox} W L + C_{ov} \cdot W$$

$$C_{sb} = A_s \cdot C_{j,area} + P_s \cdot C_{j,peri}$$

$$C_{db} = A_d \cdot C_{j,area} + P_d \cdot C_{j,peri}$$

So, in this I will write one particular form of this which is  $2 I_D$  by  $V_{GS}$  minus  $V_T$ . This is in strong inversion or  $I_D$  divided by  $\eta V_T$  were this  $V_T$  is different. It is a thermal voltage and this is in weak inversions

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$$g_{mS} = \frac{\partial I_D}{\partial V_{GS}} = \frac{\mu C_{ox}}{2} \frac{W}{L} (V_{GS} - V_T)^2 \cdot \lambda$$

$$= \lambda I_D$$

$$g_{mB} = \frac{\partial I_D}{\partial V_{GS}} = \frac{\partial I_D}{\partial V_T} \cdot \frac{\partial V_T}{\partial V_{GS}} = + \mu C_{ox} \frac{W}{L} (V_{GS} - V_T) (1 + \lambda V_{GS}) \left( \frac{\partial V_T}{\partial V_{GS}} \right)$$

$$= g_m \left( \frac{\partial V_T}{\partial V_{GS}} \right)$$

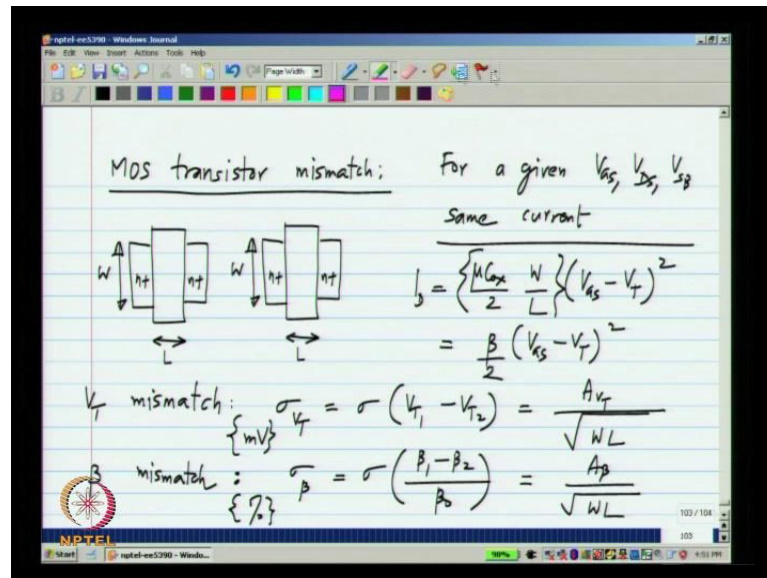
$G_{ds}$  which is  $\frac{dI_D}{dV_{DS}}$  is given by  $\mu C_{ox} \frac{W}{L} (V_{GS} - V_T)^2 \lambda$  and as before this self is the approximation by current and we will make this  $\lambda I_D$ . So, a good approximation for the value of  $G_{ds}$  is  $\lambda I_D$  and finally  $G_{mb}$  is  $\frac{dI_D}{dV_{BS}}$ . Now,  $V_{BS}$  is not explicitly a parent in the expression, but we know that  $V_T$  is a function of  $V_{BS}$ . So, what we have is let me use chain rule  $\frac{dI_D}{dV_T} \times \frac{dV_T}{dV_{BS}}$ , which gives me minus  $\mu C_{ox} \frac{W}{L} (V_{GS} - V_T)$  plus  $\lambda V_{DS} \times \frac{dV_D}{dV_{DS}}$ .

Now because  $V_{SB} = -V_{BS}$ , I can write this as  $\frac{dV_T}{dV_{SB}}$  and make this a plus sign and you also see that this part of the expression is nothing, but the  $g_m$  of the transistor. It is  $g_m \times \frac{dV_T}{dV_{SB}}$ , so it is something proportional to  $g_m$  and this  $\frac{dV_T}{dV_{SB}}$  is a number that could be of the order of let us say half to one forth or may be slightly smaller. It is not a very small number nor is it more than one, it is typically less than 1, but may be between half and one fourth or something like that, so this  $g_{mb}$ , the trans conductance from the back gate of the bulk can be a significant fraction of  $g_m$ . In some cases it is actually use for full function in circuit design, but usually the constant that you want to revise by us. The source bulk junction limits that unity of this  $g_{mb}$ , all that it can be use in many cases and some case it is an inherent. We will later see some basic circuits, where this leads to some problems.

So, this completes the small signal model and later when we realize trans conductors and opamps and so on. With our MOS transistor, we will use the small signal module to evaluate the characteristics of those blocks. So, far we have discussed the common components like a register and capacitor and we also discuss the MOS transistor in case of resistor and capacitor. We saw that when you make physically identical components, they are nominally identical. They will be a small mismatch between them and that is related to the physical size of the device and exactly the same thing is to the case of MOS transistor as well. Now, we quickly deal with mismatch in MOS transistor.



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So, let us say you make two identical MOS transistor, it will show the top view. We have some  $W$  and some  $L$  and there is the copy of this which has the same  $W$  and same  $L$ . So, this two are normally identical, that means if you buy a sheet with given  $V_{GS}$ ,  $V_{DS}$  and  $V_{SP}$ , you should get the same current as usual. It turns out the things that are not exactly identical. There are only nominal issues. There is a small difference between the two. Now, do you describe between these two incase of resistor and capacitor, you have a single parameter.

We have the resistances of the resistance we have the capacitance of the capacitance, where in case of mosfet, we seem to have many a parameters, but first of all we will use the square law model in saturation region which says that its  $\mu_{ox}$  by two by  $L$ ,  $V_{GS}$  minus  $V_T$  square and this enter multiple factors. Let me call it beta by two  $V_{GS}$  minus  $V_T$  square, Where beta is nothing but  $\mu_{Cox}$  times  $W$  by  $L$ .

So, now there are really two parameters beta and  $V_T$ . So, I will describe the mismatch and beta and  $V_T$ . What we do is let us say, we make a ten thousand pairs of this transistor and measure the different in beta and measure the different in  $V_T$  for each pair of transistors and somehow describe it and also related to the nominal value of beta and  $V_T$ . So, the  $V_T$  mismatch is described by the standard deviation of  $V_T$  and in case of  $V_T$  it is not normalizing to the nominal value  $V_T$ , this is because nominal value  $V_T$  could be 0 or a very small. It does not make a sense to normalize to nominal value of  $V_T$ .

We will see that  $V_T$  is nothing, but just the sigma of  $V_{T1}$  minus  $V_{T2}$  for each pair of transistor and this is the quantity that has dimensions of millivolts unlike the mismatch and resistor and capacitor which was that you mismatch and were dimensionless is ok. And this is given by some constant that depends on some process divided by the area of the MOS transistor exactly the same way that resistor and capacitance mismatch depends on the area and data mismatch or the current factor mismatch.

This has some nominal values in multiplying this, so this is really the sigma of  $\beta_1$  minus  $\beta_2$ , that is difference in  $\beta$  of identical pair of transistor divided by the nominal value  $\beta_0$  and this is given by a  $\beta$  by square root of  $WL$  sigma  $V_T$ , something that measure in millivolts and sigma  $\beta$  is this something measure in percent. Sigma  $\beta$  is analog to the numbers of sigma  $r$  and sigma  $c$ . So, how do we calculate the effect of this mismatches we will see that in next lecture?

Thank you